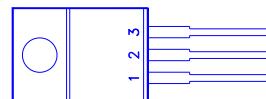
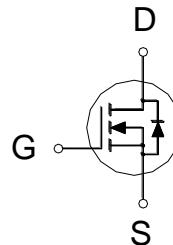


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P8010BT
TO-220
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	85mΩ	17A


 1. GATE
 2. DRAIN
 3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current $T_C = 25^\circ\text{C}$	I_D	17	A
$T_C = 100^\circ\text{C}$	I_D	10	
Pulsed Drain Current ¹	I_{DM}	35	A
Avalanche Current	I_{AS}	13	
Avalanche Energy ²	E_{AS}	8.5	mJ
Power Dissipation $T_C = 25^\circ\text{C}$	P_D	54	W
$T_C = 100^\circ\text{C}$	P_D	21	
Junction & Storage Temperature Range	T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	2.3	62.5	°C / W
Junction-to-Case				

¹Pulse width limited by maximum junction temperature.²Starting $T_j=25^\circ\text{C}$, $L=0.1\text{mH}$, $V_{DD}=50\text{V}$ **ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	1.3	1.8	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80\text{V}$, $V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 80\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 125^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}$, $I_D = 10\text{A}$		63	95	$\text{m}\Omega$
	$R_{DS(\text{ON})}$	$V_{GS} = 10\text{V}$, $I_D = 15\text{A}$		61	85	$\text{m}\Omega$

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Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 15A$		26		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		538		pF
Output Capacitance	C_{oss}			86		
Reverse Transfer Capacitance	C_{rss}			35		
Total Gate Charge ²	Q_g	$V_{DS} = 50V, I_D = 15A$ $V_{GS} = 10V$		12.7		nC
Gate-Source Charge ²	Q_{gs}			1.9		
Gate-Drain Charge ²	Q_{gd}			4.5		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 50V$ $I_D \geq 15A, V_{GS} = 10V, R_{GS} = 6\Omega$		11		nS
Rise Time ²	t_r			53		
Turn-Off Delay Time ²	$t_{d(off)}$			80		
Fall Time ²	t_f			75		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				17	A
Forward Voltage ¹	V_{SD}	$I_F = 15A, V_{GS} = 0V$			1.1	V
Reverse Recovery Time	t_{rr}	$I_F = 15A, dI_F/dt = 100A / \mu S$		33		nS
Reverse Recovery Charge	Q_{rr}			47		nC

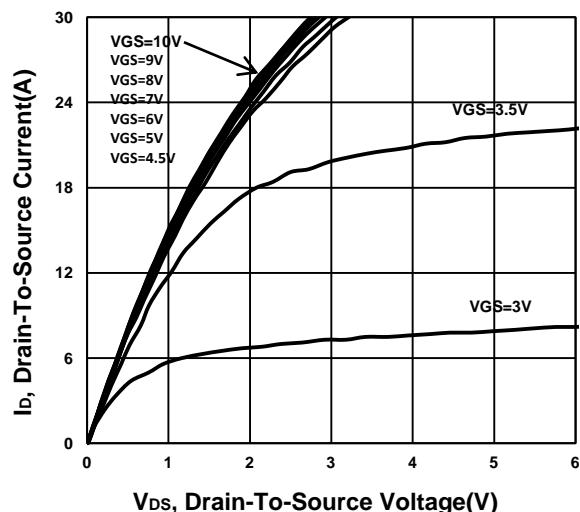
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

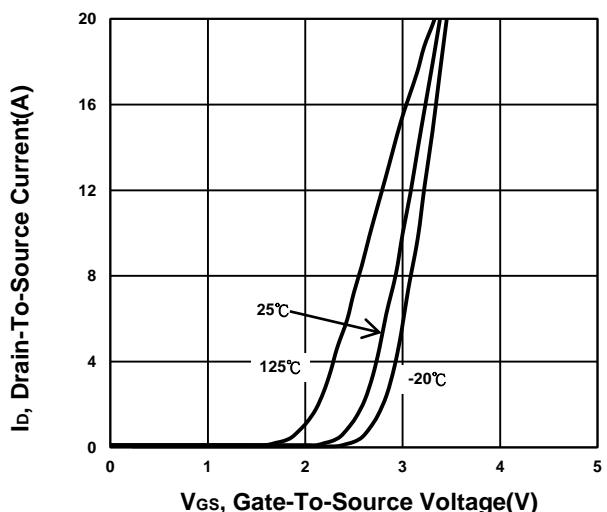
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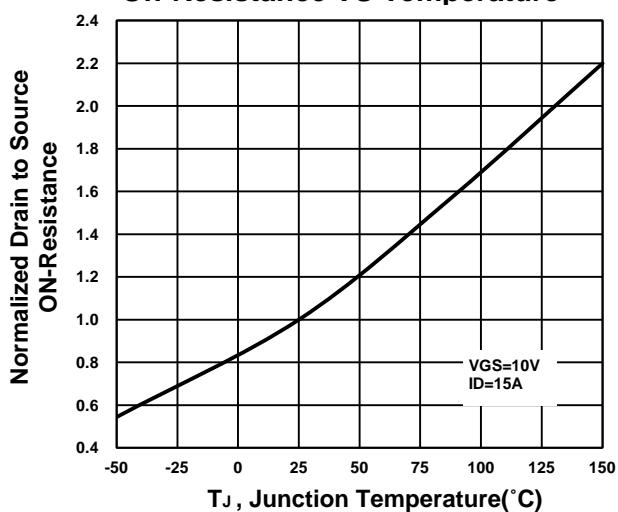
Output Characteristics



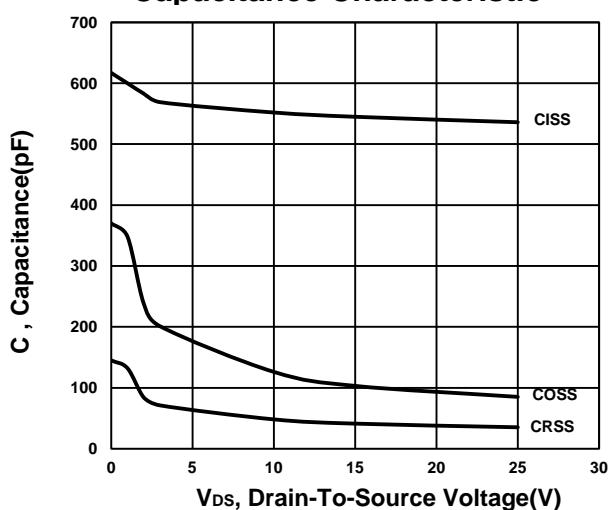
Transfer Characteristics



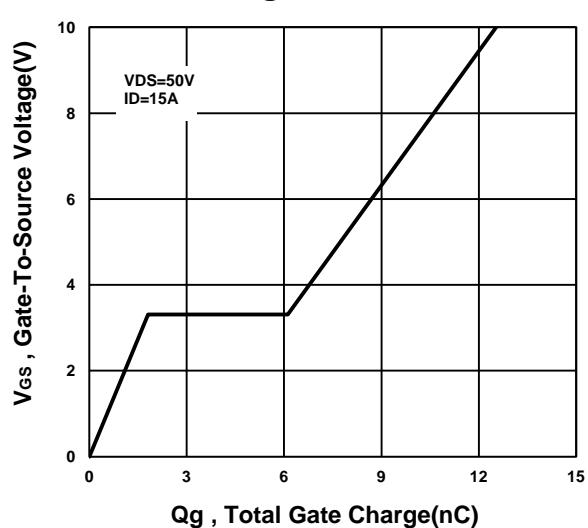
On-Resistance VS Temperature



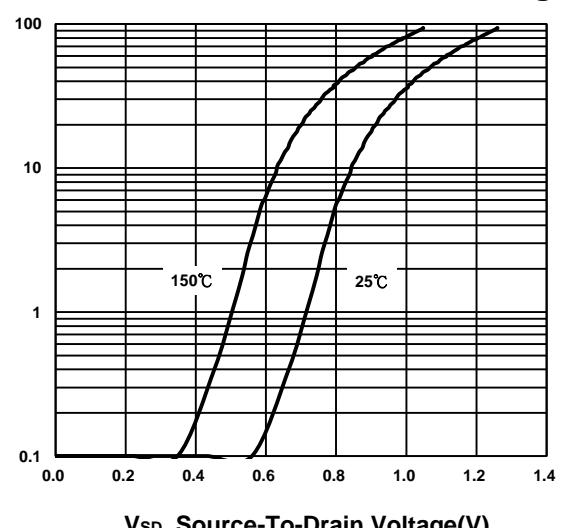
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage

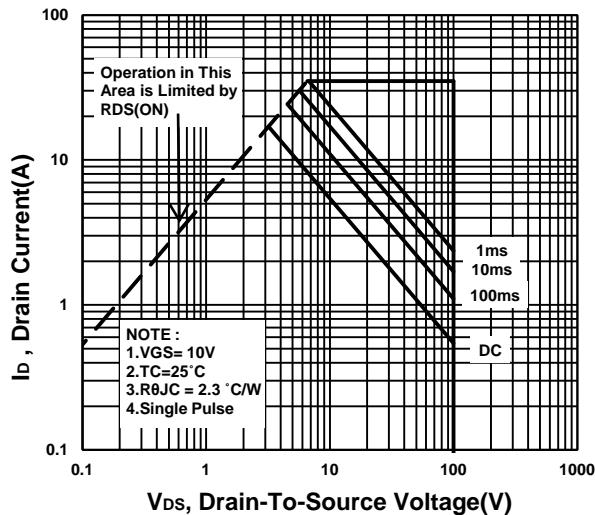


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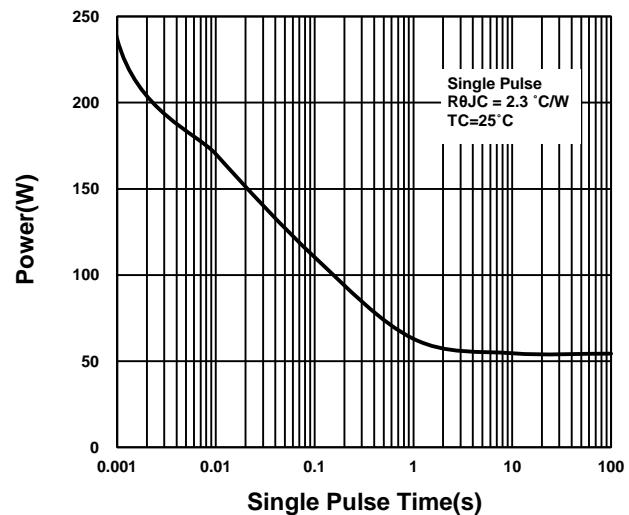
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

